

Examiner-Initiated Interview Summary	Application No. 10/651,671	Applicant(s) WEST ET AL.	
	Examiner John Kim	Art Unit 3733	

All Participants:

- (1) John Kim.
(2) Eduardo Robert.

Status of Application: pending

- (3) John Guynn.
(4) _____.

Date of Interview: 22 May 2006

Time: 6:00

Type of Interview:

- ☒ Telephonic
☐ Video Conference
☐ Personal (Copy given to: ☐ Applicant ☐ Applicant's representative)

Exhibit Shown or Demonstrated: ☐ Yes ☒ No
If Yes, provide a brief description:

Part I.

Rejection(s) discussed:
n/a

Claims discussed:
1, 11, 30, 14, 16

Prior art documents discussed:
n/a

Part II.

SUBSTANCE OF INTERVIEW DESCRIBING THE GENERAL NATURE OF WHAT WAS DISCUSSED:
See Continuation Sheet

Part III.

- ☒ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview directly resulted in the allowance of the application. The examiner will provide a written summary of the substance of the interview in the Notice of Allowability.
☐ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview did not result in resolution of all issues. A brief summary by the examiner appears in Part II above.


EDUARDO C. ROBERT
SUPERVISORY PATENT EXAMINER



(Examiner/SPE Signature)

(Applicant/Applicant's Representative Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: examiner initiated interview with applicant's representative in regards to claims 1, 11, and 30, where the limitation "sufficient space" lacked antecedent basis, thus "a" was added in front of the limitation.

In regards to claim 14, the limitation "corresponding attachment posts" lacked antecedent basis, thus "a pair of" was added in front of the limitation.

In regards to claim 16, the limitation "the first and second retention recesses" lacked antecedent basis. Thus, claim 14 has been made dependent from claim 13, where the limitation was initially presented.

See Examiner's Amendment attached hereto..